EECE.3170: Microprocessor Systems Design ISummer 2017

Lecture 5: Key Questions May 24, 2016

1.	Explain the	operation	of the	bit test	instructions	(BT,	BTR.	BTS,	BTC
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2. Explain the operation of the bit scan instructions (BSF, BSR).

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3. **Example:** Given the following initial state, list <u>all</u> changed registers and/or memory locations and their new values. Where appropriate, you should also list the state of the carry flag (CF).

<u>Initial state:</u>

EAX: 00000000n
EBX: 0000000Ah
ECX: 00000000h
EDX: 00000000h

CF: 0

ESI: 00000008h EDI: FFFF0000h

Address

- 10.0					
21100h	04	00	10	10	
21104h	89	01	20	40	
21108h	02	00	00	16	
2110Ch	17	03	FF	00	
21110h	1E	00	06	00	
21114h	80	00	0A	00	

Instructions:

BT	WORD PTR [21102h], 4
BTC	WORD PTR [21110h], 1
BTS	WORD PTR [21104h], 1
BSF	CX, WORD PTR [2110Eh]
BSR	DX, WORD PTR [21109h]